

RoHS COMPLIANT HALOGEN

FREE

SW80N08V1-1-VB Datasheet

N-Channel 80 V (D-S) MOSFET

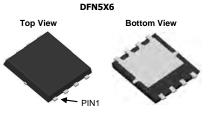
PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)			
80	0.0048 at V_{GS} = 10 V	60				
	0.0050 at V _{GS} = 7.5 V	60	25 nC			
	0.0064 at V _{GS} = 4.5 V	60				

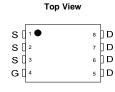
FEATURES

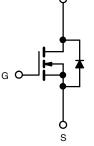
- Trench power MOSFET
- 100 % R_q and UIS tested

APPLICATIONS

- · Primary side switching
- Synchronous rectification
- DC/AC inverters







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N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	80	V	
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		60 ^a		
	T _C = 70 °C		60 ^a		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	23.8 ^{b, c}		
	T _A = 70 °C		19 ^{b, c}		
Pulsed Drain Current (t = 300 µs)		I _{DM}	100	— A	
	T _C = 25 °C		60 ^a		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	5.6 ^{b, c}		
Single Pulse Avalanche Current		I _{AS}	35		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	61	mJ	
	T _C = 25 °C		104		
Maria a Dana Distribution	T _C = 70 °C		66.6	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	6.25 ^{b, c}		
	T _A = 70 °C		4 b, c		
Operating Junction and Storage Temperature R	T _J , T _{stg}	-55 to 150			
Soldering Recommendations (Peak Temperatur	*	260			

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	15	20	°C/W			
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	0.9	1.2	0/00			

Notes

a. Package limited.

b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s. d. The DFN 5Xx6 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework conditions: Manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under steady state conditions is 54 °C/W.

SPECIFICATIONS (T _J = 25 °C, ι	inless other	wise noted)						
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit		
Static						-		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$	80	-	-	V		
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	1 2504	-	47	-	mV/°C		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-5.7	-	mv/°C		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	1.2	-	2.8	V		
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$	-	-	± 100	nA		
Zere Osta Valla na Dusia Ormant		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	1			
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 ^{\circ}\text{C}$	-	-	10	μΑ		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 V$, $V_{GS} = 10 V$	30	-	-	А		
		V _{GS} = 10 V, I _D = 20 A	-	0.0048	-	1		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 7.5 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	-	0.0050	-	Ω		
		V _{GS} = 4.5 V, I _D = 15 A	-	0.0064	-	-		
Forward Transconductance a	9 _{fs}	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	-	68	-	S		
Dynamic ^b								
Input Capacitance	C _{iss}		-	2800	-			
Output Capacitance	C _{oss}	V _{DS} = 40 V, V _{GS} = 0 V, f = 1 MHz	-	1100	-	pF		
Reverse Transfer Capacitance	C _{rss}		-	93	-			
· · · · · · · · · · · · · · · · · · ·	Qg	V _{DS} = 40 V, V _{GS} = 10 V, I _D = 20 A	-	57	86	-		
Total Gate Charge		$V_{DS} = 40 \text{ V}, V_{GS} = 7.5 \text{ V}, I_D = 20 \text{ A}$	-	42	63			
-			-	25	38	nC		
Gate-Source Charge	Q _{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$	-	8.5	-			
Gate-Drain Charge	Q _{gd}		-	10	-			
Output Charge	Q _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}$	-	70	105			
Gate Resistance	Rg	f = 1 MHz	0.3	0.95	1.9	Ω		
Turn-On Delay Time	t _{d(on)}		-	9	18			
Rise Time	t _r	$V_{DD} = 40 \text{ V}, \text{ R}_{L} = 2 \Omega$	-	12	24	-		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	34	68			
Fall Time	t _f		-	7	14			
Turn-On Delay Time	t _{d(on)}		-	16	32	ns		
Rise Time	t _r	$V_{DD} = 40 \text{ V}. \text{ R}_{1} = 2 \Omega$	-	15	30	-		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 20 \text{ A}, V_{\text{GEN}} = 7.5 \text{ V}, R_g = 1 \Omega$	-	32	64			
Fall Time	t _f	-	-	8	16			
Drain-Source Body Diode Characteristic	1 · ·			1		L		
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	60			
Pulse Diode Forward Current ^a	I _{SM}		-	-	100	A		
Body Diode Voltage	V _{SD}	I _S = 5 A	-	0.73	1.1	V		
Body Diode Reverse Recovery Time	t _{rr}		-	53	105	ns		
Body Diode Reverse Recovery Charge	Q _{rr}		-	65	130	nC		
Reverse Recovery Fall Time	ta	I_F = 20 A, dl/dt = 100 A/µs, T _J = 25 °C	-	25	-			
Reverse Recovery Rise Time	t _a		-	28	-	ns		

Notes

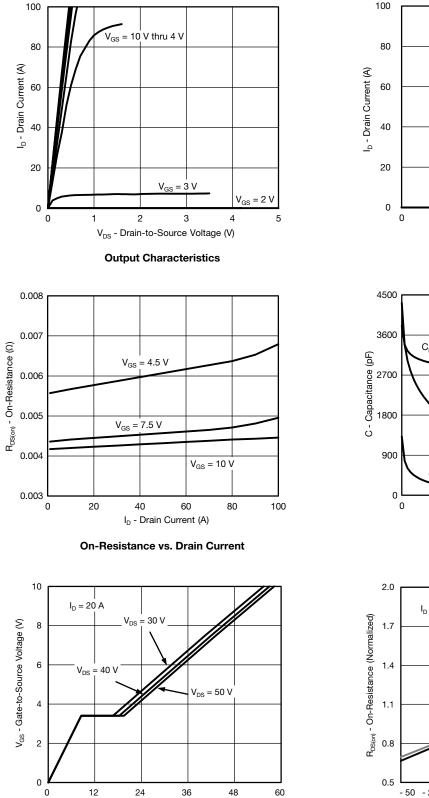
a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$

b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

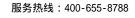
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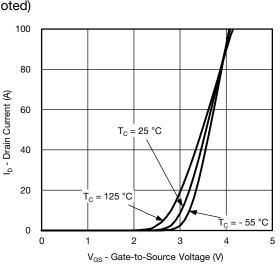




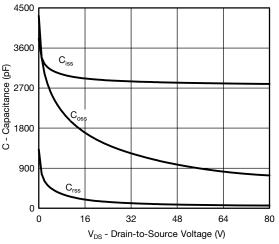


Q_g - Total Gate Charge (nC)

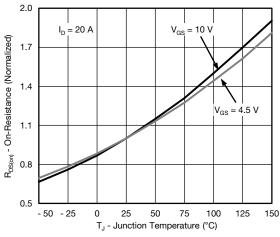




Transfer Characteristics

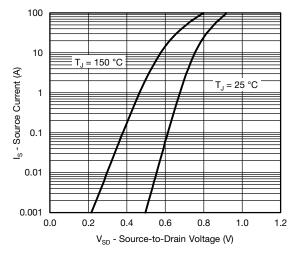




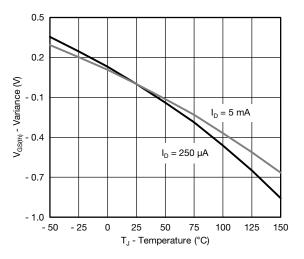


On-Resistance vs. Junction Temperature

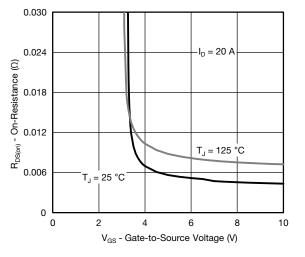




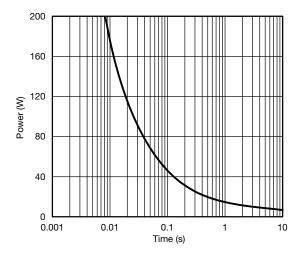
Source-Drain Diode Forward Voltage



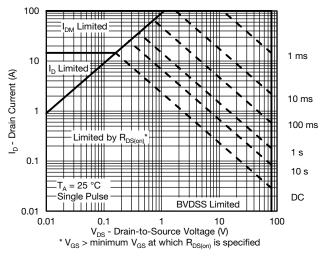




On-Resistance vs. Gate-to-Source Voltage

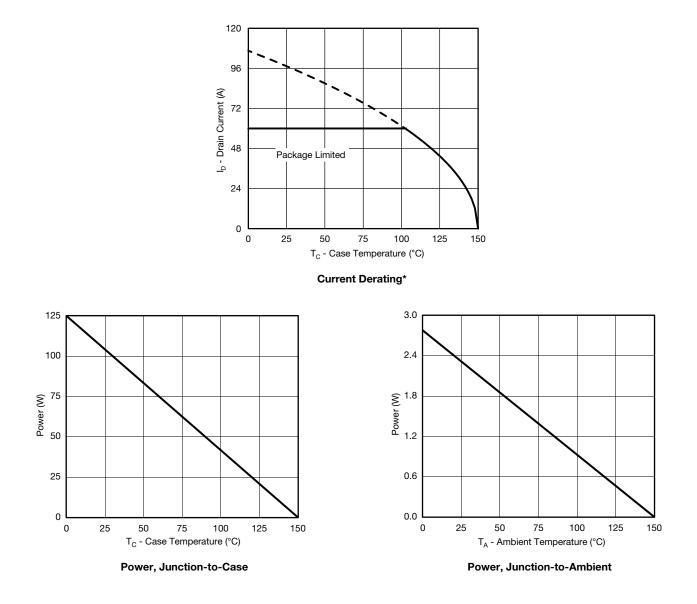


Single Pulse Power, Junction-to-Ambient



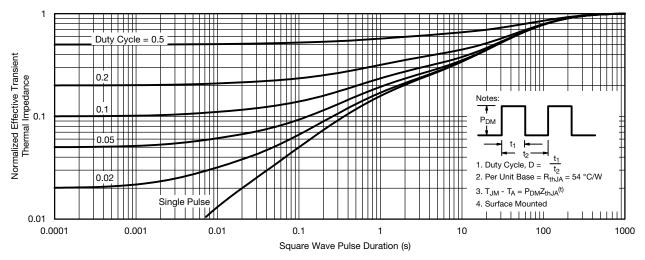
Safe Operating Area, Junction-to-Ambient

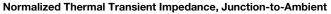


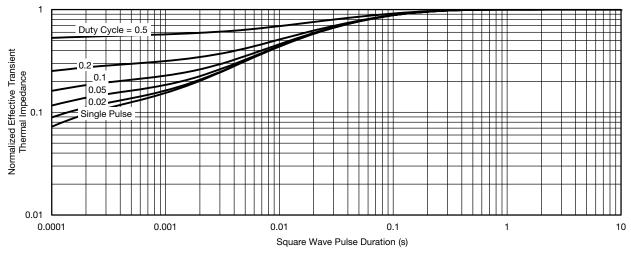


* The power dissipation P_D is based on $T_{J \text{ (max.)}} = 150 \text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



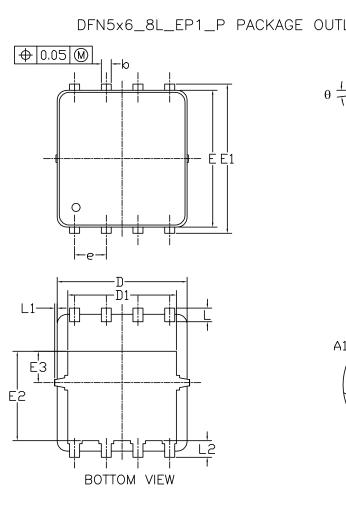






Normalized Thermal Transient Impedance, Junction-to-Case





DFN5x6_8L_EP1_P PACKAGE OUTLIN

A1

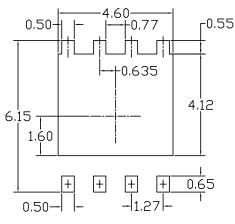
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VIEW 'A'

VIEW 'A' (SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES			
STMBOLS	MIN	NOM	MAX	MIN	NOM	MAX	
А	0.85	0.95	1.00	0.033	0.037	0.039	
A1	0.00		0.05	0.000		0.002	
b	0.30	0.40	0.50	0.012	0.016	0.020	
с	0.15 0.20		0.25	0.006	0.008	0.010	
D	5.10	5.20	5.30	0.201	0.205	0.209	
D1	4.25	4.35	4.45	0.167	0.171	0.175	
Е	5.45	5.55	5.65	0.215	0.219	0.222	
E1	5.95	6.05	6.15	0.234	0.238	0.242	
E2	3.525	3.625	3.725	0.139	0.143	0.147	
E3	1.175	1.275	1.375	0.046	0.050	0.054	
e	1.27 BSC			0.050 BSC			
L	0.45	0.55	0.65	0.018	0.022	0.026	
L1	0		0.15	0		0.006	
L2	0.68 REF			0.027 REF			
θ	0° 10°		0°		10°		

NOTE

UNIT: mm

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.

MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH. 2. CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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